

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,367	LEE ET AL.	
Examiner	Art Unit	
Chau N. Nguven	2831	

			ORIG	INAL		CROSS REFERENCE(S)										
CLASS SUBCLASS				SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)										
174 102SC																
INT	ERN	ATIC	NAL	CLASSIFICATION												
н о	0	1	В	1/00												
				1												
	1			1												
				1												
				1							·					
N/A (Assistant Examiner) (Date)					e)	C	hang	yen 11-12	Total Claims Allowed: 1							
Doian Grand "/23/07									O. Print C	O.G. Print Fi						
(Legal Instruments Examiner) (Date)					(Date)	(Pr	imary Examine		1							

X	laims	ns renumbered in the same order as presented by applicant									□ СРА		☐ T.D.		 ☐ R.1.47			
Final	Original		Final	Original		Final	Original		Final	Original		Final	Original		Final	Original	Final	Original
	1			31			61			91			121			151		181
	2			32			62			92			122			152		182
	3			33			63			93			123			153		183
	4			34			64			94			124			154		184
	5			35			65			95			125			155		185
	6			36			66			96			126			156		186
	7			37			67			97			127			157		187
	8			38			68			98			128			158		188
1	9			39			69			99			129			159		189
	10			40			70			100			130			160	L	190
	11			41			71			101			131			161		191
	12			42			72			102			132			162		192
	13			43			73			103			133			163		193
	14			44			74			104			134			164		194
	15			45			75			105			135			165		195
	16			46			76			106			136			166		196
	17			47			77			107			137			167		197
	18			48			78		Í	108			138			168		198
	19			49			79			109			139			169		199
	20_			50			80			110			140			170		200
	21			51			81			111			141			171		201
	22			52			82			112			142			172		202
	23			53			83			113			143			173		203
	24			54			84			114			144			174		204
	25			55			85			115			145			175		205
	26			56			86			116			146			176		206
	27			57			87			117			147			177		207
	28			58_			88			118			148			178		208
	29			59			89			119			149			179		209
	30			60			90			120			150			180		210